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LHF00L30
Flash Memory
16M (1Mb x 16)
(Model Number: LHF00L30)

Spec. Issue Date: May 25, 2004
Spec No: FM045024

SPEC No.	FM045024
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ISSUE:	May. 25, 2004
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To; _____

PRELIMINARY
S P E C I F I C A T I O N S

Product Type 16 Mbit Flash Memory

L H F 0 0 L 3 0

Model No. (L H F 0 0 L 3 0)

This device specification is subject to change without notice.

* This specifications contains 26 pages including the cover and appendix.

* Refer to LHF00LXX series Appendix (FUM03802).

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LHF00L30

16Mbit (1Mbit×16)

Flash MEMORY

- 16-M density with 16-bit I/O Interface
- Read Operation
 - 70ns
- Low Power Operation
 - 2.7V Read and Write Operations
 - V_{CCQ} for Input/Output Power Supply Isolation
 - Automatic Power Savings Mode reduces I_{CCR} in Static Mode
- Enhanced Code + Data Storage
 - 5 μ s Typical Erase/Program Suspend
- OTP (One Time Program) Block
 - 4-Word Factory-Programmed Area
 - 4-Word User-Programmable Area
- Operating Temperature -40°C to +85°C
- CMOS Process (P-type silicon substrate)
- Flexible Blocking Architecture
 - Eight 4-Kword Parameter Blocks
 - One 32-Kword Block
 - Fifteen 64-Kword Blocks
 - Top Parameter Location
- Enhanced Data Protection Features
 - Individual Block Lock and Block Lock-Down with Zero-Latency
 - All blocks are locked at power-up or device reset.
 - Absolute Protection with $V_{PP} \leq V_{PPLK}$
 - Block Erase, Full Chip Erase, Word Program Lockout during Power Transitions
- Automated Erase/Program Algorithms
 - 3.0V Low-Power 10 μ s/Word (Typ.) Programming
 - 12.0V No Glue Logic 9 μ s/Word (Typ.) Production Programming and 0.8s Erase (Typ.)
- Cross-Compatible Command Support
 - Basic Command Set
 - Common Flash Interface (CFI)
- Extended Cycling Capability
 - Minimum 100,000 Block Erase Cycles
- 48-Lead TSOP (Normal Bend)
- ETOXTM* Flash Technology
- Not designed or rated as radiation hardened

The product is a low power, high density, low cost, nonvolatile read/write storage solution for a wide range of applications. The product can operate at $V_{CC}=2.7V-3.6V$ and $V_{PP}=1.65V-3.6V$ or $11.7V-12.3V$. Its low voltage operation capability greatly extends battery life for portable applications.

The memory array block architecture utilizes Enhanced Data Protection features, which provides maximum flexibility for safe nonvolatile code and data storage.

Special OTP (One Time Program) block provides an area to store permanent code such as an unique number.

* ETOX is a trademark of Intel Corporation.

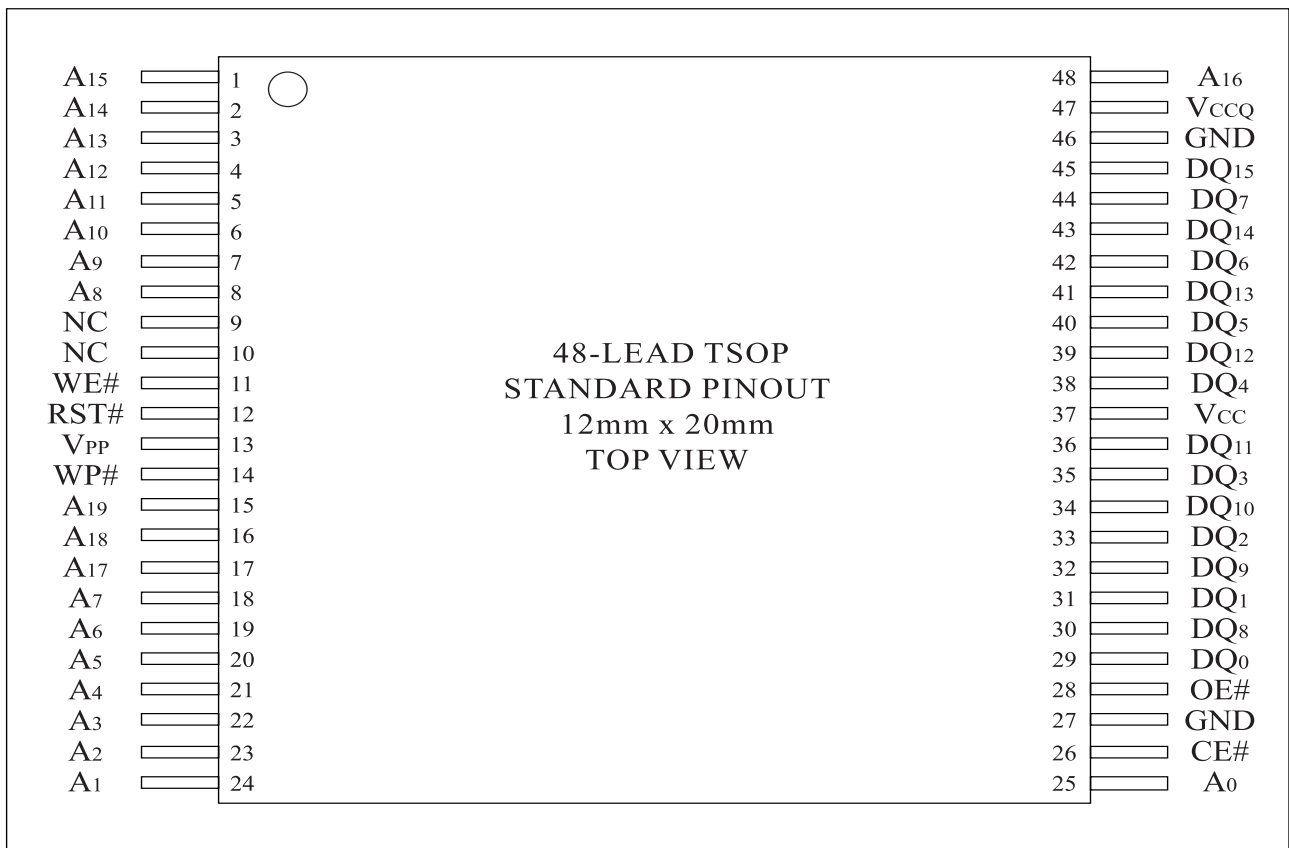


Figure 1. 48-Lead TSOP (Normal Bend) Pinout

Table 1. Pin Descriptions

Symbol	Type	Name and Function
$A_{19}-A_0$	INPUT	ADDRESS INPUTS: Inputs for addresses.
$DQ_{15}-DQ_0$	INPUT/ OUTPUT	DATA INPUTS/OUTPUTS: Inputs data and commands during CUI (Command User Interface) write cycles, outputs data during memory array, status register, query code, identifier code reads. Data pins float to high-impedance (High Z) when the chip or outputs are deselected. Data is internally latched during an erase or program cycle.
CE#	INPUT	CHIP ENABLE: Activates the device's control logic, input buffers, decoders and sense amplifiers. CE#-high (V_{IH}) deselects the device and reduces power consumption to standby levels.
RST#	INPUT	RESET: When low (V_{IL}), RST# resets internal automation and inhibits write operations which provides data protection. RST#-high (V_{IH}) enables normal operation. After power-up or reset mode, the device is automatically set to read array mode. RST# must be low during power-up/down.
OE#	INPUT	OUTPUT ENABLE: Gates the device's outputs during a read cycle.
WE#	INPUT	WRITE ENABLE: Controls writes to the CUI and array blocks. Addresses and data are latched on the rising edge of CE# or WE# (whichever goes high first).
WP#	INPUT	WRITE PROTECT: When WP# is V_{IL} , locked-down blocks cannot be unlocked. Erase or program operation can be executed to the blocks which are not locked and not locked-down. When WP# is V_{IH} , lock-down is disabled.
V_{PP}	INPUT/SUPPLY	MONITORING POWER SUPPLY VOLTAGE: V_{PP} is not used for power supply pin. With $V_{PP} \leq V_{PPLK}$, block erase, full chip erase, program or OTP program cannot be executed and should not be attempted. Applying $12.0V \pm 0.3V$ to V_{PP} provides fast erasing or fast programming mode. In this mode, V_{PP} is power supply pin. Applying $12.0V \pm 0.3V$ to V_{PP} during erase/program can only be done for a maximum of 1,000 cycles on each block. V_{PP} may be connected to $12.0V \pm 0.3V$ for a total of 80 hours maximum. Use of this pin at $12.0V + 0.3V$ beyond these limits may reduce block cycling capability or cause permanent damage.
V_{CC}	SUPPLY	DEVICE POWER SUPPLY (2.7V-3.6V): With $V_{CC} \leq V_{LKO}$, all write attempts to the flash memory are inhibited. Device operations at invalid V_{CC} voltage (see DC Characteristics) produce spurious results and should not be attempted.
V_{CCQ}	SUPPLY	INPUT/OUTPUT POWER SUPPLY (2.7V-3.6V): Power supply for all input/output pins.
GND	SUPPLY	GROUND: Do not float any ground pins.
NC		NO CONNECT: Lead is not internally connected; it may be driven or floated.

[A₁₉-A₀]

FFFF	4-Kword Block 23
FF000	
FEFFF	4-Kword Block 22
FE000	
FDFFF	4-Kword Block 21
FD000	
FCFFF	4-Kword Block 20
FC000	
FBFFF	4-Kword Block 19
FB000	
FAFFF	4-Kword Block 18
FA000	
F9FFF	4-Kword Block 17
F9000	
F8FFF	4-Kword Block 16
F8000	
F7FFF	32-Kword Block 15
F0000	
EFFFF	64-Kword Block 14
E0000	
DFFFF	64-Kword Block 13
D0000	
CFFFF	64-Kword Block 12
C0000	
BFFFF	64-Kword Block 11
B0000	
AFFFF	64-Kword Block 10
A0000	
9FFFF	64-Kword Block 9
90000	
8FFFF	64-Kword Block 8
80000	
7FFFF	64-Kword Block 7
70000	
6FFFF	64-Kword Block 6
60000	
5FFFF	64-Kword Block 5
50000	
4FFFF	64-Kword Block 4
40000	
3FFFF	64-Kword Block 3
30000	
2FFFF	64-Kword Block 2
20000	
1FFFF	64-Kword Block 1
10000	
0FFFF	64-Kword Block 0
00000	

Figure 2. Memory Map (Top Parameter)

Table 2. Identifier Codes and OTP Address for Read Operation

	Code	Address [A ₁₉ -A ₀]	Data [DQ ₁₅ -DQ ₀]	Notes
Manufacturer Code	Manufacturer Code	00000H	00B0H	
Device Code	Device Code	00001H	00A4H	
Block Lock Configuration Code	Block is Unlocked	Block Address + 2	DQ ₀ = 0	1
	Block is Locked		DQ ₀ = 1	1
	Block is not Locked-Down		DQ ₁ = 0	1
	Block is Locked-Down		DQ ₁ = 1	1
OTP	OTP Lock	00080H	OTP-LK	2
	OTP	00081-00088H	OTP	3

NOTES:

1. Block Address = The beginning location of a block address. DQ₁₅-DQ₂ are reserved for future implementation.
2. OTP-LK=OTP Block Lock configuration.
3. OTP=OTP Block data.

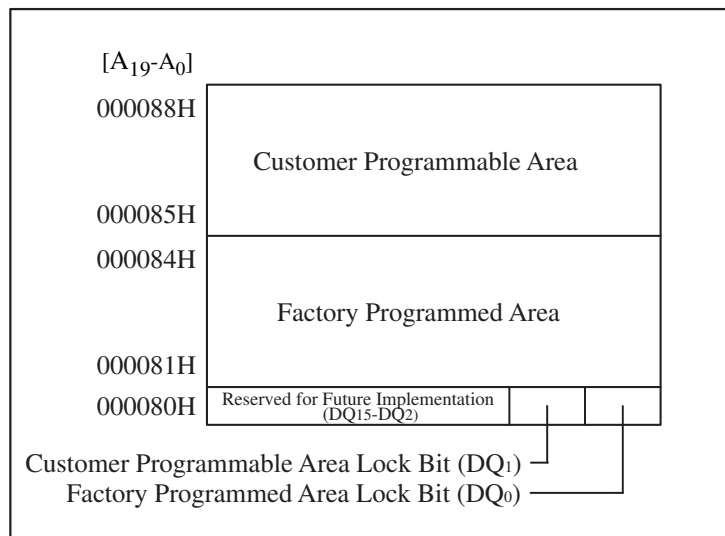


Figure 3. OTP Block Address Map for OTP Program
(The area outside 80H~88H cannot be used.)

Table 3. Bus Operation^(1, 2)

Mode	Notes	RST#	CE#	OE#	WE#	Address	V _{PP}	DQ ₁₅₋₀
Read Array	6	V _{IH}	V _{IL}	V _{IL}	V _{IH}	X	X	D _{OUT}
Output Disable		V _{IH}	V _{IL}	V _{IH}	V _{IH}	X	X	High Z
Standby		V _{IH}	V _{IH}	X	X	X	X	High Z
Reset	3	V _{IL}	X	X	X	X	X	High Z
Read Identifier Codes/OTP	6	V _{IH}	V _{IL}	V _{IL}	V _{IH}	See Table 2	X	See Table 2
Read Query	6,7	V _{IH}	V _{IL}	V _{IL}	V _{IH}	See Appendix	X	See Appendix
Read Status Register	6	V _{IH}	V _{IL}	V _{IL}	V _{IH}	X	X	D _{OUT}
Write	4,5,6	V _{IH}	V _{IL}	V _{IH}	V _{IL}	X	V _{PPH1/2}	D _{IN}

NOTES:

1. Refer to DC Characteristics. When $V_{PP} \leq V_{PPLK}$, memory contents can be read, but cannot be altered.
2. X can be V_{IL} or V_{IH} for control pins and addresses, and V_{PPLK} or V_{PPH1/2} for V_{PP}. Refer to DC Characteristics for V_{PPLK} and V_{PPH1/2} voltages.
3. RST# at GND±0.2V ensures the lowest power consumption.
4. Command writes involving block erase, full chip erase, program or OTP program are reliably executed when $V_{PP} = V_{PPH1/2}$ and $V_{CC} = 2.7V - 3.6V$.
5. Refer to Table 4 for valid D_{IN} during a write operation.
6. Never hold OE# low and WE# low at the same timing.
7. Refer to Appendix of LHF00LXX series for more information about query code.

Table 4. Command Definitions⁽¹⁰⁾

Command	Bus Cycles Req'd	Notes	First Bus Cycle			Second Bus Cycle		
			Oper ⁽¹⁾	Addr ⁽²⁾	Data	Oper ⁽¹⁾	Addr ⁽²⁾	Data ⁽³⁾
Read Array	1		Write	X	FFH			
Read Identifier Codes/OTP	≥ 2	4	Write	X	90H	Read	IA or OA	ID or OD
Read Query	≥ 2	4	Write	X	98H	Read	QA	QD
Read Status Register	2		Write	X	70H	Read	X	SRD
Clear Status Register	1		Write	X	50H			
Block Erase	2	5	Write	BA	20H	Write	BA	D0H
Full Chip Erase	2	5, 8	Write	X	30H	Write	X	D0H
Program	2	5,6	Write	WA	40H or 10H	Write	WA	WD
Block Erase and Program Suspend	1	7, 8	Write	X	B0H			
Block Erase and Program Resume	1	7, 8	Write	X	D0H			
Set Block Lock Bit	2		Write	BA	60H	Write	BA	01H
Clear Block Lock Bit	2	9	Write	BA	60H	Write	BA	D0H
Set Block Lock-down Bit	2		Write	BA	60H	Write	BA	2FH
OTP Program	2	8	Write	OA	C0H	Write	OA	OD

NOTES:

- Bus operations are defined in Table 3.
- All addresses which are written at the first bus cycle should be the same as the addresses which are written at the second bus cycle.
X=Any valid address within the device.
IA=Identifier codes address (See Table 2).
QA=Query codes address. Refer to Appendix of LHF00LXX series for details.
BA=Address within the block being erased, set/cleared block lock bit or set block lock-down bit.
WA=Address of memory location for the Program command.
OA=Address of OTP block to be read or programmed (See Figure 3).
- ID=Data read from identifier codes. (See Table 2).
QD=Data read from query database. Refer to Appendix of LHF00LXX series for details.
SRD=Data read from status register. See Table 8 for a description of the status register bits.
WD=Data to be programmed at location WA. Data is latched on the rising edge of WE# or CE# (whichever goes high first) during command write cycles.
OD=Data within OTP block. Data is latched on the rising edge of WE# or CE# (whichever goes high first) during command write cycles.
- Following the Read Identifier Codes/OTP command, read operations access manufacturer code, device code, block lock configuration code and the data within OTP block (See Table 2).
The Read Query command is available for reading CFI (Common Flash Interface) information.
- Block erase, full chip erase or program cannot be executed when the selected block is locked. Unlocked block can be erased or programmed when RST# is V_{IH}.
- Either 40H or 10H are recognized by the CUI (Command User Interface) as the program setup.
- If the program operation and the erase operation are both suspended, the suspended program operation will be resumed first.
- Full chip erase and OTP program operations can not be suspended. The OTP Program command can not be accepted while the block erase operation is being suspended.

9. Following the Clear Block Lock Bit command, block which is not locked-down is unlocked when WP# is V_{IL} . When WP# is V_{IH} , lock-down bit is disabled and the selected block is unlocked regardless of lock-down configuration.
10. Commands other than those shown above are reserved by SHARP for future device implementations and should not be used.

Table 5. Functions of Block Lock⁽⁵⁾ and Block Lock-Down

Current State					Erase/Program Allowed ⁽²⁾
State	WP#	DQ ₁ ⁽¹⁾	DQ ₀ ⁽¹⁾	State Name	
[000]	0	0	0	Unlocked	Yes
[001] ⁽³⁾	0	0	1	Locked	No
[011]	0	1	1	Locked-down	No
[100]	1	0	0	Unlocked	Yes
[101] ⁽³⁾	1	0	1	Locked	No
[110] ⁽⁴⁾	1	1	0	Lock-down Disable	Yes
[111]	1	1	1	Lock-down Disable	No

NOTES:

1. DQ₀=1: a block is locked; DQ₀=0: a block is unlocked.
DQ₁=1: a block is locked-down; DQ₁=0: a block is not locked-down.
2. Erase and program are general terms, respectively, to express: block erase, full chip erase and program operations.
3. At power-up or device reset, all blocks default to locked state and are not locked-down, that is, [001] (WP#=0) or [101] (WP#=1), regardless of the states before power-off or reset operation.
4. When WP# is driven to V_{IL} in [110] state, the state changes to [011] and the blocks are automatically locked.
5. OTP (One Time Program) block has the lock function which is different from those described above.

Table 6. Block Locking State Transitions upon Command Write⁽⁴⁾

Current State				Result after Lock Command Written (Next State)		
State	WP#	DQ ₁	DQ ₀	Set Lock ⁽¹⁾	Clear Lock ⁽¹⁾	Set Lock-down ⁽¹⁾
[000]	0	0	0	[001]	No Change	[011] ⁽²⁾
[001]	0	0	1	No Change ⁽³⁾	[000]	[011]
[011]	0	1	1	No Change	No Change	No Change
[100]	1	0	0	[101]	No Change	[111] ⁽²⁾
[101]	1	0	1	No Change	[100]	[111]
[110]	1	1	0	[111]	No Change	[111] ⁽²⁾
[111]	1	1	1	No Change	[110]	No Change

NOTES:

1. "Set Lock" means Set Block Lock Bit command, "Clear Lock" means Clear Block Lock Bit command and "Set Lock-down" means Set Block Lock-Down Bit command.
2. When the Set Block Lock-Down Bit command is written to the unlocked block (DQ₀=0), the corresponding block is locked-down and automatically locked at the same time.
3. "No Change" means that the state remains unchanged after the command written.
4. In this state transitions table, assumes that WP# is not changed and fixed V_{IL} or V_{IH}.

Table 7. Block Locking State Transitions upon WP# Transition⁽⁴⁾

Previous State	Current State				Result after WP# Transition (Next State)	
	State	WP#	DQ ₁	DQ ₀	WP#=0→1 ⁽¹⁾	WP#=1→0 ⁽¹⁾
-	[000]	0	0	0	[100]	-
-	[001]	0	0	1	[101]	-
[110] ⁽²⁾	[011]	0	1	1	[110]	-
Other than [110] ⁽²⁾					[111]	-
-	[100]	1	0	0	-	[000]
-	[101]	1	0	1	-	[001]
-	[110]	1	1	0	-	[011] ⁽³⁾
-	[111]	1	1	1	-	[011]

NOTES:

1. "WP#=0→1" means that WP# is driven to V_{IH} and "WP#=1→0" means that WP# is driven to V_{IL}.
2. State transition from the current state [011] to the next state depends on the previous state.
3. When WP# is driven to V_{IL} in [110] state, the state changes to [011] and the blocks are automatically locked.
4. In this state transitions table, assumes that lock configuration commands are not written in previous, current and next state.

Table 8. Status Register Definition

R	R	R	R	R	R	R	R
15	14	13	12	11	10	9	8
WSMS	BESS	BEFCES	POPS	VPPS	PSS	DPS	R
7	6	5	4	3	2	1	0

<p>SR.15 - SR.8 = RESERVED FOR FUTURE ENHANCEMENTS (R)</p> <p>SR.7 = WRITE STATE MACHINE STATUS (WSMS) 1 = Ready 0 = Busy</p> <p>SR.6 = BLOCK ERASE SUSPEND STATUS (BESS) 1 = Block Erase Suspended 0 = Block Erase in Progress/Completed</p> <p>SR.5 = BLOCK ERASE AND FULL CHIP ERASE STATUS (BEFCES) 1 = Error in Block Erase or Full Chip Erase 0 = Successful Block Erase or Full Chip Erase</p> <p>SR.4 = PROGRAM AND OTP PROGRAM STATUS (POPS) 1 = Error in Program or OTP Program 0 = Successful Program or OTP Program</p> <p>SR.3 = V_{PP} STATUS (VPPS) 1 = V_{PP} LOW Detect, Operation Abort 0 = V_{PP} OK</p> <p>SR.2 = PROGRAM SUSPEND STATUS (PSS) 1 = Program Suspended 0 = Program in Progress/Completed</p> <p>SR.1 = DEVICE PROTECT STATUS (DPS) 1 = Erase or Program Attempted on a Locked Block, Operation Abort 0 = Unlocked</p> <p>SR.0 = RESERVED FOR FUTURE ENHANCEMENTS (R)</p>	<p>NOTES:</p> <p>Status Register indicates the status of the WSM (Write State Machine).</p> <p>Check SR.7 to determine block erase, full chip erase, program or OTP program completion. SR.6 - SR.1 are invalid while SR.7="0".</p> <p>If both SR.5 and SR.4 are "1"s after a block erase, full chip erase, program, set/clear block lock bit, set block lock-down bit attempt, an improper command sequence was entered.</p> <p>SR.3 does not provide a continuous indication of V_{PP} level. The WSM interrogates and indicates the V_{PP} level only after Block Erase, Full Chip Erase, Program or OTP Program command sequences. SR.3 is not guaranteed to report accurate feedback when V_{PP}≠V_{PPH1}, V_{PPH2} or V_{PPLK}.</p> <p>SR.1 does not provide a continuous indication of block lock bit. The WSM interrogates the block lock bit only after Block Erase, Full Chip Erase, Program or OTP Program command sequences. It informs the system, depending on the attempted operation, if the block lock bit is set. Reading the block lock configuration codes after writing the Read Identifier Codes/OTP command indicates block lock bit status.</p> <p>SR.15 - SR.8 and SR.0 are reserved for future use and should be masked out when polling the status register.</p>
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1 Electrical Specifications

1.1 Absolute Maximum Ratings *

Operating Temperature

During Read, Erase and Program ...-40°C to +85°C ⁽¹⁾

Storage Temperature

During under Bias..... -40°C to +85°C

During non Bias..... -65°C to +125°C

Voltage On Any Pin (except V_{CC}, V_{CCQ} and V_{PP})

..... -0.5V to V_{CCQ}+0.5V ⁽²⁾

V_{CC} and V_{CCQ} Supply Voltage

-0.2V to +3.9V ⁽²⁾

V_{PP} Supply Voltage

-0.2V to +12.6V ^(2, 3, 4)

Output Short Circuit Current

100mA ⁽⁵⁾

***WARNING:** Stressing the device beyond the "Absolute Maximum Ratings" may cause permanent damage. These are stress ratings only. Operation beyond the "Operating Conditions" is not recommended and extended exposure beyond the "Operating Conditions" may affect device reliability.

NOTES:

1. Operating temperature is for extended temperature product defined by this specification.
2. All specified voltages are with respect to GND. Minimum DC voltage is -0.5V on input/output pins and -0.2V on V_{CC}, V_{CCQ} and V_{PP} pins. During transitions, this level may undershoot to -2.0V for periods <20ns. Maximum DC voltage on input/output pins is V_{CC}+0.5V which, during transitions, may overshoot to V_{CC}+2.0V for periods <20ns.
3. Maximum DC voltage on V_{PP} may overshoot to +13.0V for periods <20ns.
4. V_{PP} erase/program voltage is normally 2.7V-3.6V. Applying 11.7V-12.3V to V_{PP} during erase/program can be done for a maximum of 1,000 cycles on each block. V_{PP} may be connected to 11.7V-12.3V for a total of 80 hours maximum.
5. Output shorted for no more than one second. No more than one output shorted at a time.

1.2 Operating Conditions

Parameter	Symbol	Min.	Typ.	Max.	Unit	Notes
Operating Temperature	T _A	-40	+25	+85	°C	
V _{CC} Supply Voltage	V _{CC}	2.7	3.0	3.6	V	1
I/O Supply Voltage	V _{CCQ}	2.7	3.0	3.6	V	1
V _{PP} Voltage when Used as a Logic Control	V _{PPH1}	1.65	3.0	3.6	V	1
V _{PP} Supply Voltage	V _{PPH2}	11.7	12.0	12.3	V	1, 2
Block Erase Cycling: V _{PP} =V _{PPH1}		100,000			Cycles	
Block Erase Cycling: V _{PP} =V _{PPH2} , 80 hrs.				1,000	Cycles	
Maximum V _{PP} hours at V _{PPH2}				80	Hours	

NOTES:

1. See DC Characteristics tables for voltage range-specific specification.
2. Applying V_{PP}=11.7V-12.3V during a erase or program can be done for a maximum of 1,000 cycles on each block. A permanent connection to V_{PP}=11.7V-12.3V is not allowed and can cause damage to the device.

1.2.1 Capacitance ⁽¹⁾ ($T_A=+25^{\circ}\text{C}$, $f=1\text{MHz}$)

Parameter	Symbol	Condition	Min.	Typ.	Max.	Unit
Input Capacitance	C_{IN}	$V_{IN}=0.0\text{V}$		4	7	pF
Output Capacitance	C_{OUT}	$V_{OUT}=0.0\text{V}$		6	10	pF

NOTE:

1. Sampled, not 100% tested.

1.2.2 AC Input/Output Test Conditions

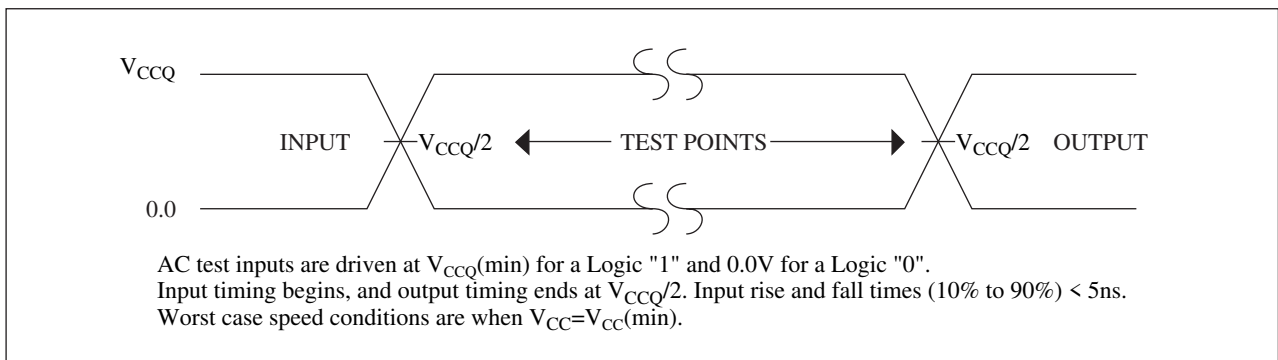


Figure 4. Transient Input/Output Reference Waveform for $V_{CC}=2.7\text{V}-3.6\text{V}$

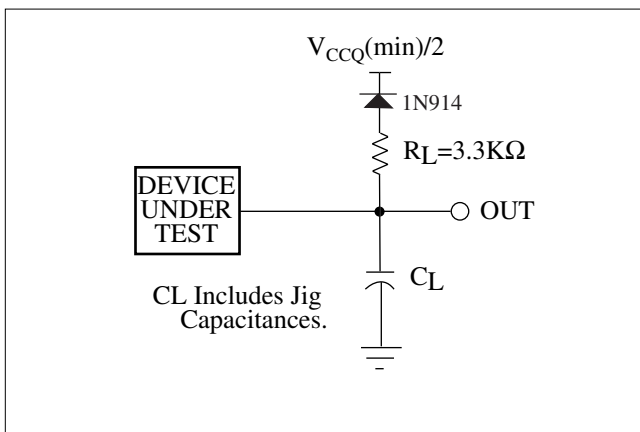


Figure 5. Transient Equivalent Testing Load Circuit

Table 9. Test Configuration Capacitance Loading Value

Test Configuration	C_L (pF)
$V_{CC}=2.7\text{V}-3.6\text{V}$	50

1.2.3 DC Characteristics

 $V_{CC}=2.7V-3.6V$

Symbol	Parameter	Notes	Min.	Typ.	Max.	Unit	Test Conditions
I_{LI}	Input Load Current	1	-1.0		+1.0	μA	$V_{CC}=V_{CCMax.}$,
I_{LO}	Output Leakage Current	1	-1.0		+1.0	μA	$V_{CCQ}=V_{CCQMax.}$, $V_{IN}/V_{OUT}=V_{CCQ}$ or GND
I_{CCS}	V_{CC} Standby Current	1,7		4	10	μA	$V_{CC}=V_{CCMax.}$, CE#=RST#= $V_{CCQ}\pm 0.2V$, WP#= V_{CCQ} or GND
I_{CCAS}	V_{CC} Automatic Power Savings Current	1,4,7		4	10	μA	$V_{CC}=V_{CCMax.}$, CE#=GND $\pm 0.2V$, WP#= V_{CCQ} or GND
I_{CCD}	V_{CC} Reset Current	1,7		4	10	μA	RST#=GND $\pm 0.2V$
I_{CCR}	V_{CC} Read Current	1,7			17	mA	$V_{CC}=V_{CCMax.}$, CE#= V_{IL} , OE#= V_{IH} , f=5MHz
I_{CCW}	V_{CC} Program Current	1,5,7		20	60	mA	$V_{PP}=V_{PPH1}$
		1,5,7		10	20	mA	$V_{PP}=V_{PPH2}$
I_{CCE}	V_{CC} Block Erase, Full Chip Erase Current	1,5,7		10	30	mA	$V_{PP}=V_{PPH1}$
		1,5,7		4	10	mA	$V_{PP}=V_{PPH2}$
I_{CCWS} I_{CCES}	V_{CC} Program or Block Erase Suspend Current	1,2,7		10	200	μA	CE#= V_{IH}
I_{PPS} I_{PPR}	V_{PP} Standby or Read Current	1,6,7		2	5	μA	$V_{PP}\leq V_{CC}$
I_{PPW}	V_{PP} Program Current	1,5,6,7		2	5	μA	$V_{PP}=V_{PPH1}$
		1,5,6,7		10	30	mA	$V_{PP}=V_{PPH2}$
I_{PPE}	V_{PP} Block Erase, Full Chip Erase Current	1,5,6,7		2	5	μA	$V_{PP}=V_{PPH1}$
		1,5,6,7		5	15	mA	$V_{PP}=V_{PPH2}$
I_{PPWS}	V_{PP} Program Suspend Current	1,6,7		2	5	μA	$V_{PP}=V_{PPH1}$
		1,6,7		10	200	μA	$V_{PP}=V_{PPH2}$
I_{PPES}	V_{PP} Block Erase Suspend Current	1,6,7		2	5	μA	$V_{PP}=V_{PPH1}$
		1,6,7		10	200	μA	$V_{PP}=V_{PPH2}$

DC Characteristics (Continued)

$$V_{CC}=2.7V-3.6V$$

Symbol	Parameter	Notes	Min.	Typ.	Max.	Unit	Test Conditions
V _{IL}	Input Low Voltage	5	-0.4		0.4	V	
V _{IH}	Input High Voltage	5	2.4		V _{CCQ} + 0.4	V	
V _{OL}	Output Low Voltage	5			0.2	V	V _{CC} =V _{CC} Min., V _{CCQ} =V _{CCQ} Min., I _{OL} =100μA
V _{OH}	Output High Voltage	5	V _{CCQ} -0.2			V	V _{CC} =V _{CC} Min., V _{CCQ} =V _{CCQ} Min., I _{OH} =-100μA
V _{PPLK}	V _{PP} Lockout during Normal Operations	3,5,6			0.4	V	
V _{PPH1}	V _{PP} during Block Erase, Full Chip Erase, Program or OTP Program Operations	6	1.65	3.0	3.6	V	
V _{PPH2}	V _{PP} during Block Erase, Full Chip Erase, Program or OTP Program Operations	6	11.7	12.0	12.3	V	
V _{LKO}	V _{CC} Lockout Voltage		1.5			V	

NOTES:

- All currents are in RMS unless otherwise noted. Typical values are the reference values at V_{CC}=3.0V, V_{CCQ}=3.0V and T_A=+25°C unless V_{CC} is specified.
- I_{CCWS} and I_{CCES} are specified with the device de-selected. If read or program is executed while in block erase suspend mode, the device's current draw is the sum of I_{CCES} and I_{CCR} or I_{CCW}. If read is executed while in program suspend mode, the device's current draw is the sum of I_{CCWS} and I_{CCR}.
- Block erase, full chip erase, program and OTP program are inhibited when V_{PP} ≤ V_{PPLK}, and not guaranteed in the range between V_{PPLK}(max.) and V_{PPH1}(min.), between V_{PPH1}(max.) and V_{PPH2}(min.), and above V_{PPH2}(max.).
- The Automatic Power Savings (APS) feature automatically places the device in power save mode after read cycle completion. Standard address access timings (t_{AVQV}) provide new data when addresses are changed.
- Sampled, not 100% tested.
- V_{PP} is not used for power supply pin. With V_{PP} ≤ V_{PPLK}, block erase, full chip erase, program and OTP program cannot be executed and should not be attempted.
Applying 12.0V±0.3V to V_{PP} provides fast erasing or fast programming mode. In this mode, V_{PP} is power supply pin and supplies the memory cell current for block erasing and programming. Use similar power supply trace widths and layout considerations given to the V_{CC} power bus.
Applying 12.0V±0.3V to V_{PP} during erase/program can only be done for a maximum of 1,000 cycles on each block. V_{PP} may be connected to 12.0V±0.3V for a total of 80 hours maximum.
- For all pins other than those shown in test conditions, input level is V_{CCQ} or GND.

1.2.4 AC Characteristics - Read-Only Operations⁽¹⁾

$$V_{CC}=2.7V-3.6V, T_A=-40^{\circ}C \text{ to } +85^{\circ}C$$

Symbol	Parameter	Notes	Min.	Max.	Unit
t_{AVAV}	Read Cycle Time		70		ns
t_{AVQV}	Address to Output Delay			70	ns
t_{ELQV}	CE# to Output Delay	3		70	ns
t_{GLQV}	OE# to Output Delay	3		20	ns
t_{PHQV}	RST# High to Output Delay			150	ns
t_{EHQZ}, t_{GHQZ}	CE# or OE# to Output in High Z, Whichever Occurs First	2		20	ns
t_{ELQX}	CE# to Output in Low Z	2	0		ns
t_{GLQX}	OE# to Output in Low Z	2	0		ns
t_{OH}	Output Hold from First Occurring Address, CE# or OE# change	2	0		ns

NOTES:

1. See AC input/output reference waveform for timing measurements and maximum allowable input slew rate.
2. Sampled, not 100% tested.
3. OE# may be delayed up to $t_{ELQV} - t_{GLQV}$ after the falling edge of CE# without impact to t_{ELQV} .

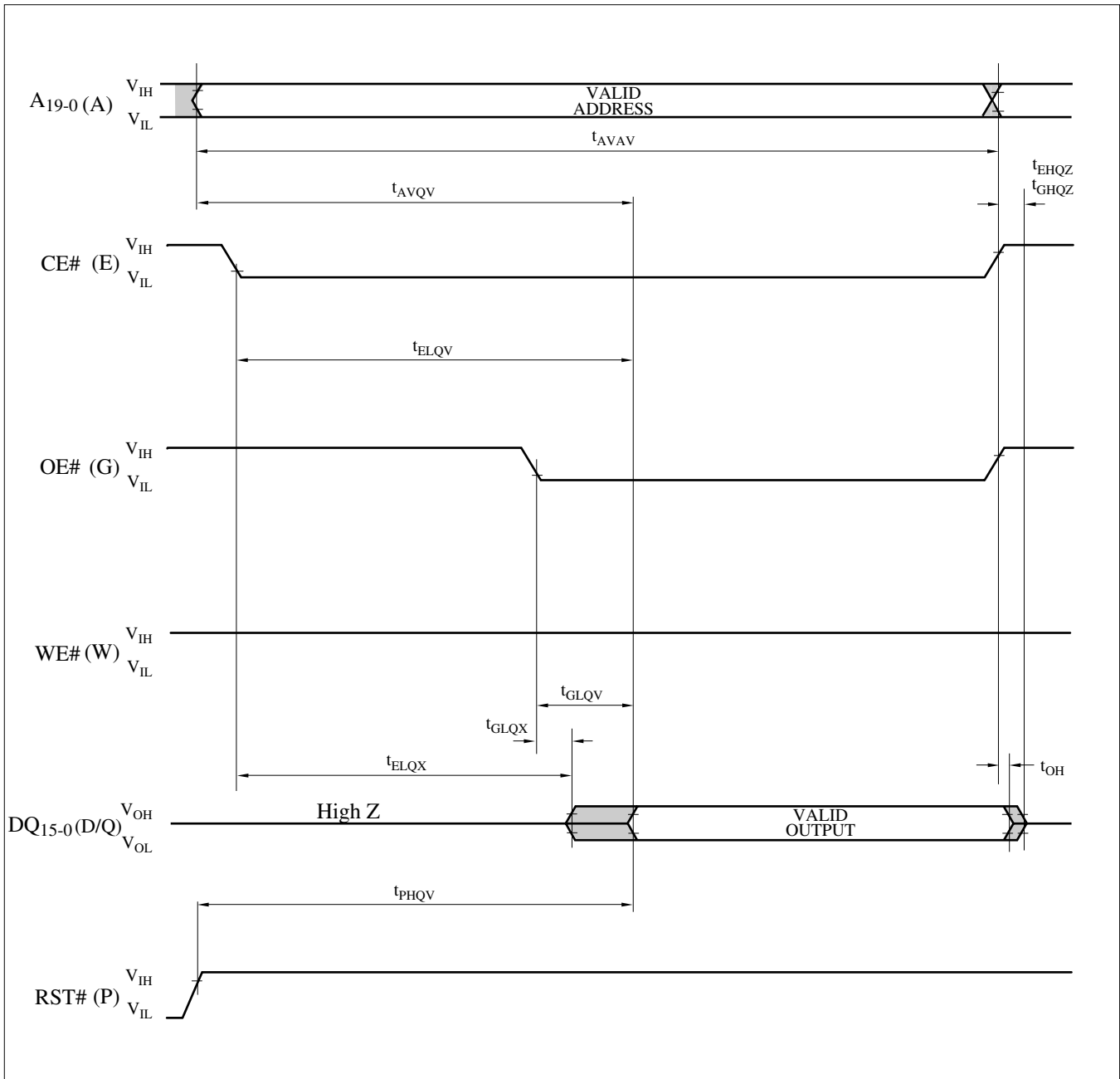


Figure 6. AC Waveform for Read Operations

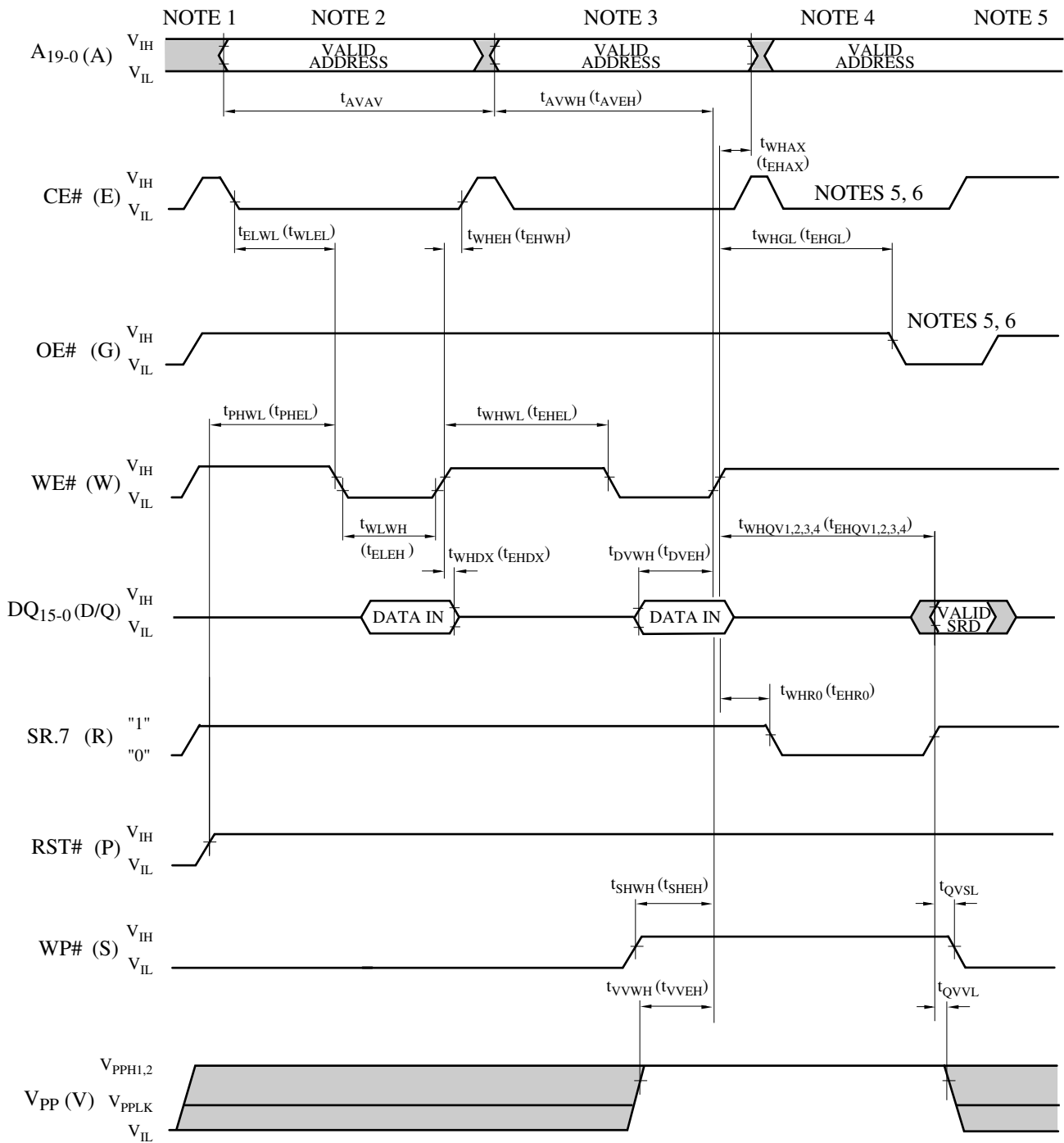
1.2.5 AC Characteristics - Write Operations^{(1), (2)}

$$V_{CC}=2.7V-3.6V, T_A=-40^{\circ}C \text{ to } +85^{\circ}C$$

Symbol	Parameter	Notes	Min.	Max.	Unit
t_{AVAV}	Write Cycle Time		70		ns
t_{PHWL} (t_{PHEL})	RST# High Recovery to WE# (CE#) Going Low	3	150		ns
t_{ELWL} (t_{WLEL})	CE# (WE#) Setup to WE# (CE#) Going Low		0		ns
t_{WLWH} (t_{ELEH})	WE# (CE#) Pulse Width	4	50		ns
t_{DVWH} (t_{DVEH})	Data Setup to WE# (CE#) Going High	8	40		ns
t_{AVWH} (t_{AVEH})	Address Setup to WE# (CE#) Going High	8	50		ns
t_{WHEH} (t_{EHWL})	CE# (WE#) Hold from WE# (CE#) High		0		ns
t_{WHDX} (t_{EHDH})	Data Hold from WE# (CE#) High		0		ns
t_{WHAX} (t_{EHAX})	Address Hold from WE# (CE#) High		0		ns
t_{WHWL} (t_{EHEL})	WE# (CE#) Pulse Width High	5	20		ns
t_{SHWH} (t_{SHEH})	WP# High Setup to WE# (CE#) Going High	3	0		ns
t_{VVWH} (t_{VVEH})	V_{PP} Setup to WE# (CE#) Going High	3	200		ns
t_{WHGL} (t_{EHGL})	Write Recovery before Read		30		ns
t_{QVSL}	WP# High Hold from Valid SRD	3, 6	0		ns
t_{QVVL}	V_{PP} Hold from Valid SRD	3, 6	0		ns
t_{WHR0} (t_{EHR0})	WE# (CE#) High to SR.7 Going "0"	3, 7		$t_{AVQV}+$ 50	ns

NOTES:

1. The timing characteristics for reading the status register during block erase, full chip erase, program and OTP program operations are the same as during read-only operations. Refer to AC Characteristics for read-only operations.
2. A write operation can be initiated and terminated with either CE# or WE#.
3. Sampled, not 100% tested.
4. Write pulse width (t_{WP}) is defined from the falling edge of CE# or WE# (whichever goes low last) to the rising edge of CE# or WE# (whichever goes high first). Hence, $t_{WP}=t_{WLWH}=t_{ELEH}=t_{WLEH}=t_{ELWH}$.
5. Write pulse width high (t_{WPH}) is defined from the rising edge of CE# or WE# (whichever goes high first) to the falling edge of CE# or WE# (whichever goes low last). Hence, $t_{WPH}=t_{WHWL}=t_{EHEL}=t_{WHEL}=t_{EHWL}$.
6. V_{PP} should be held at $V_{PP}=V_{PPH1/2}$ until determination of block erase, full chip erase, program or OTP program success (SR.1/3/4/5=0).
7. t_{WHR0} (t_{EHR0}) after the Read Query or Read Identifier Codes/OTP command= $t_{AVQV}+100ns$.
8. Refer to Table 4 for valid address and data for block erase, full chip erase, program, OTP program or lock bit configuration.



- NOTES:
1. V_{CC} power-up and standby.
 2. Write each first cycle command.
 3. Write each second cycle command or valid address and data.
 4. Automated erase or program delay.
 5. Read status register data.
 6. For read operation, OE# and CE# must be driven active, and WE# de-asserted.

Figure 7. AC Waveform for Write Operations

1.2.6 Reset Operations

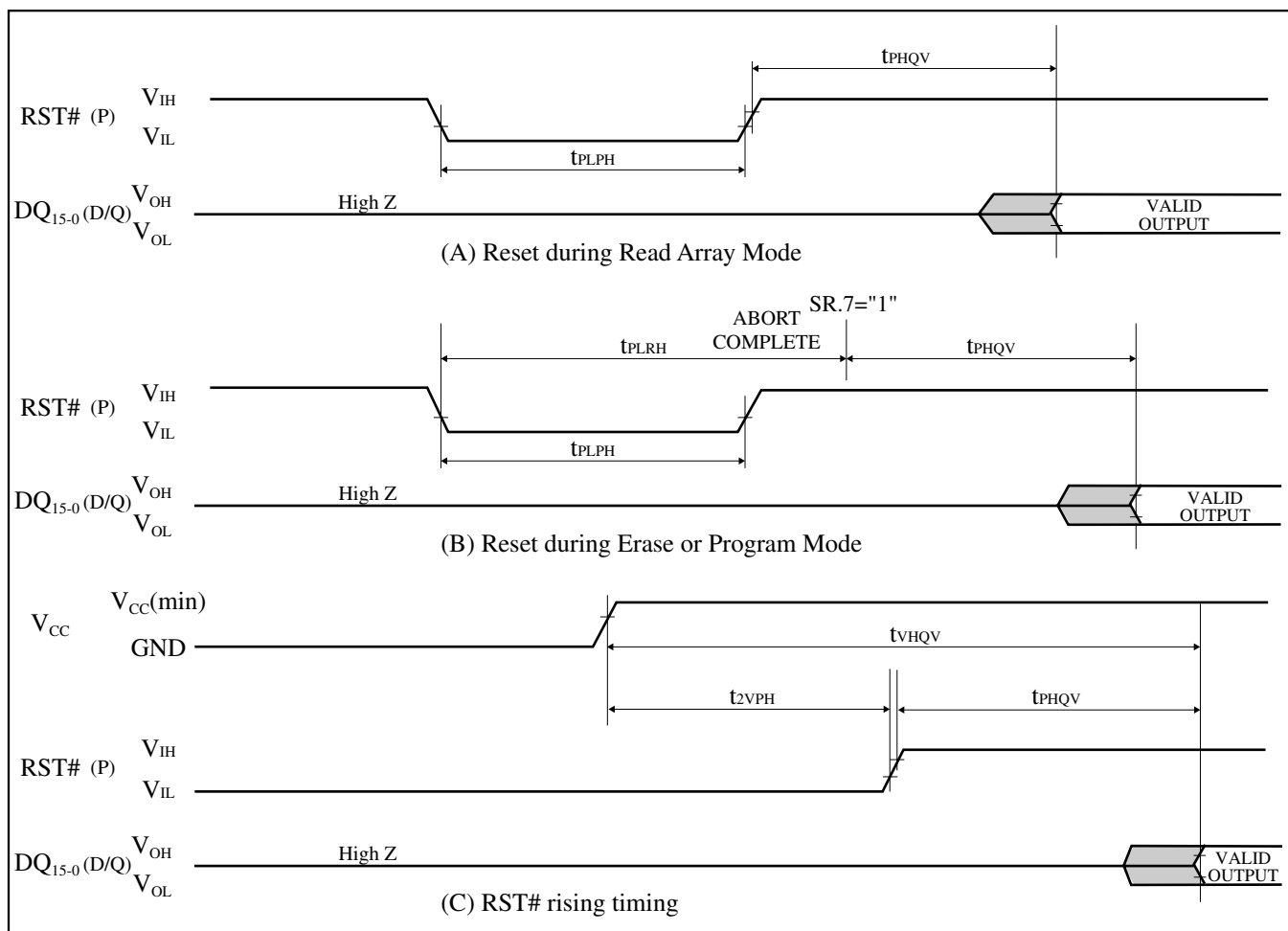


Figure 8. AC Waveform for Reset Operations

Reset AC Specifications ($V_{CC}=2.7V-3.6V$, $T_A=-40^{\circ}C$ to $+85^{\circ}C$)

Symbol	Parameter	Notes	Min.	Max.	Unit
t_{PLPH}	RST# Low to Reset during Read (RST# should be low during power-up.)	1, 2, 3	100		ns
t_{PLRH}	RST# Low to Reset during Erase or Program	1, 3, 4		22	μs
t_{2VPH}	V_{CC} 2.7V to RST# High	1, 3, 5	100		ns
t_{VHQP}	V_{CC} 2.7V to Output Delay	3		1	ms

NOTES:

1. A reset time, t_{PHQV} , is required from the later of SR.7 going "1" or RST# going high until outputs are valid. Refer to AC Characteristics - Read-Only Operations for t_{PHQV} .
2. t_{PLPH} is <100ns the device may still reset but this is not guaranteed.
3. Sampled, not 100% tested.
4. If RST# asserted while a block erase, full chip erase, program or OTP program operation is not executing, the reset will complete within 100ns.
5. When the device power-up, holding RST# low minimum 100ns is required after V_{CC} has been in predefined range and also has been in stable there.